

# Today's complexity in validation requires automation by a machine-learning based tool

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# Lisa Taubensee

- M.A.Sc. University of Waterloo Canada (2005) Characterization Engineer/AE Gennum Corp. (2001-2006) Application Engineer (AE) Texas Instruments (2007-2014) Application Engineer (AE) Synopsys (2014-2019) Application Engineer (AE) Advantest (2020 present)
- Currently supporting post silicon validation solutions Interested in new validation methodologies
- Interested in the whole validation chain



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# Complexity Demands New Post Silicon Validation Methodology

Complexities: Design performance & modes, process, IP blocks, global teams



**PSV** must ensure that (physical) chip & FW meet <u>all</u> specifications <u>after tuning</u> under <u>all</u> operating conditions & modes with sufficient <u>yield</u>.



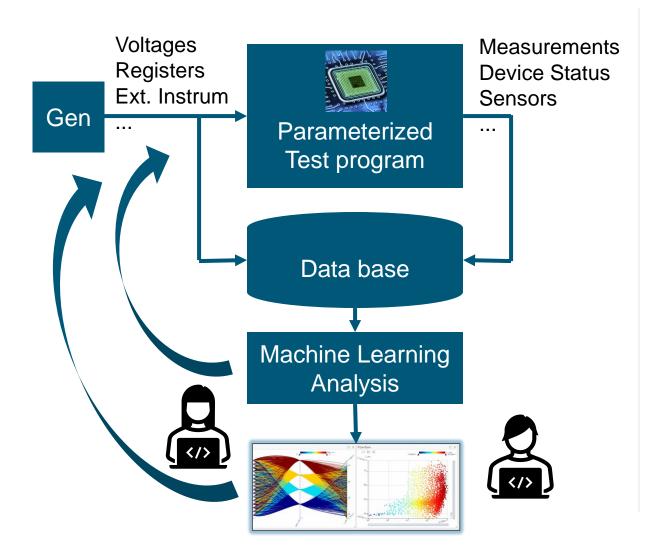
**Today's PSV** relies on expert knowledge / <u>assumptions</u>. Shmoos scan <u>expected</u> dependencies.



#### Challenges

- Process variations, design complexity and black-box IP blocks lead to <u>unexpected</u>, hard to debug problems under peculiar conditions
- Schedule pressure
- Increasing quality expectations
- Complex collaboration between global teams
- Tuning becomes too complex
- Few experts

# **New PSV Methodology**



#### Parameterized test program

- Vary everything, measure everything
- Validates chip + FW + test program

#### **Quality through black-box coverage**

- No assumptions → Constrained random tests
- **Coverage metrics**

#### **Self-learning device exploration loop**

#### Relate inputs to outputs

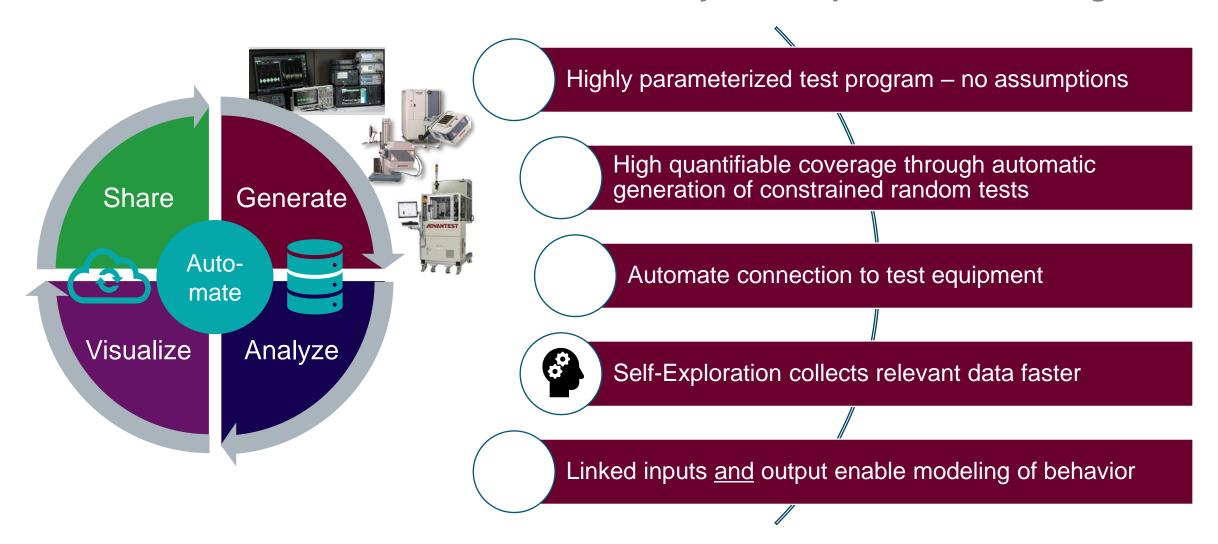
- **Create model**
- **Identify important influences**
- **Debugging & tuning tools**

#### Interactive post-processing analysis

- **Based on comprehensive data**
- **Generate more data from within plots**

## Generate

Parameterize and execute test cases automatically for comprehensive coverage



# Random Coverage is Much Higher Than Shmoo Coverage

Scenario: 25 inputs, want to cover all 10% value intervals, 10k test cases.

There are 300 pairs of 25 variables, and 2300 triples.

**Shmoo:** Select 100 suspected most relevant input pairs, run 10x10 Shmoo for each pair.

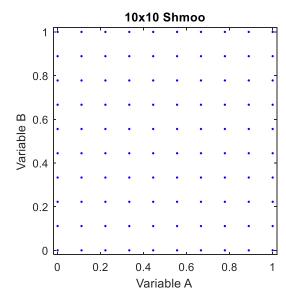
Pair Coverage: 33 %

(100 % for 100 pairs, 0 % for 200 pairs)

Triple Coverage: 0 %, only pairs were covered.

Shmoos show 100 slices of reality.

Shmoo tests can find only expected problems.

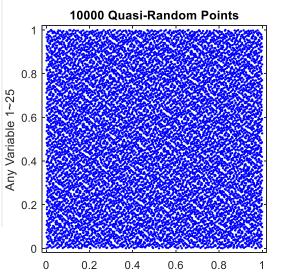


Random Test: Randomize all input variables simultaneously. Make no assumption!

Pair Coverage: 100 % across all 300 pairs

Still 100 % with 1k test cases

**Triple Coverage: 100 %** across all 2300 triples 99.5 % with 3k test cases



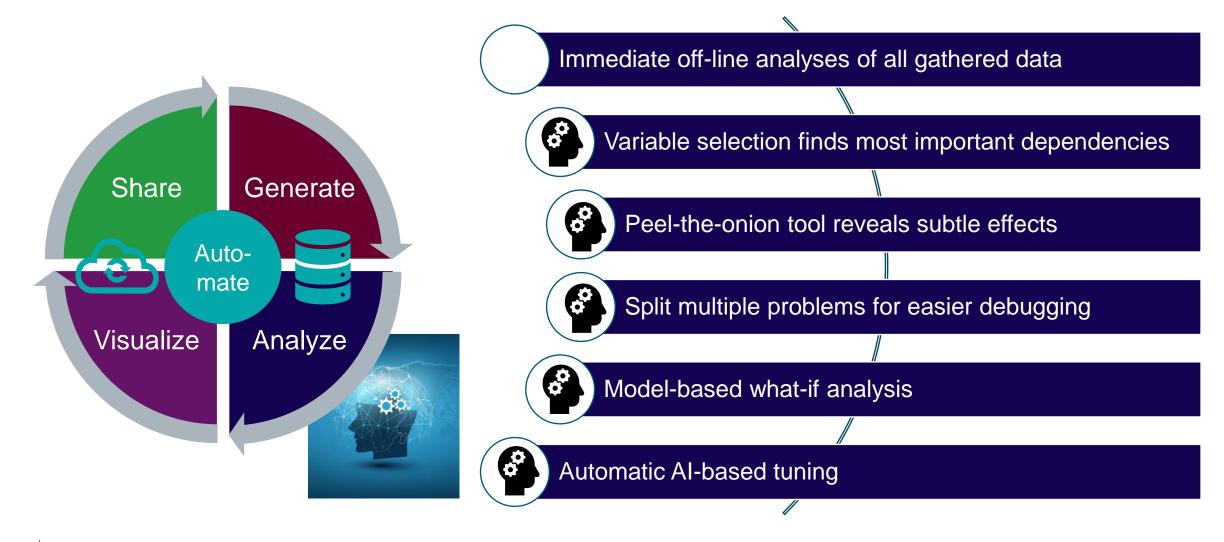
Any Variable 1~25

Random tests reveal the whole truth.

Random tests find also unexpected problems.

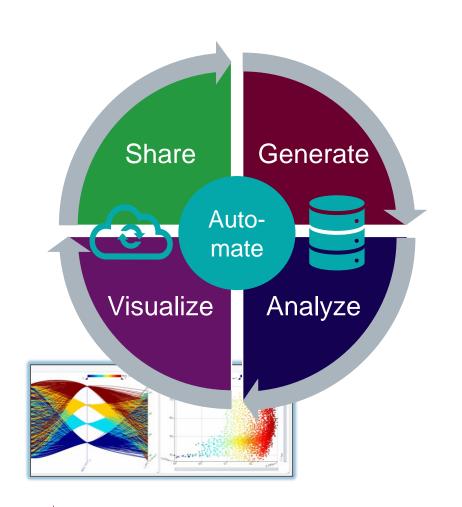
# **Analyze**

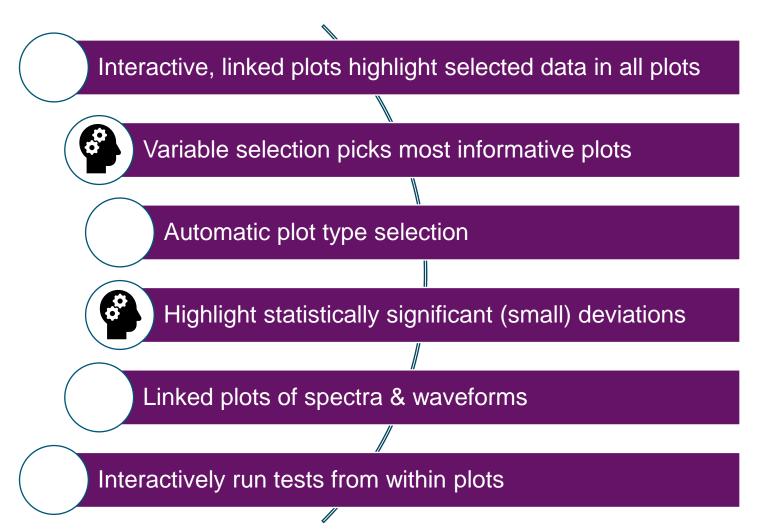
Analyze data immediately as off-line experiments, powered by PSV-specific Al



## **Visualize**

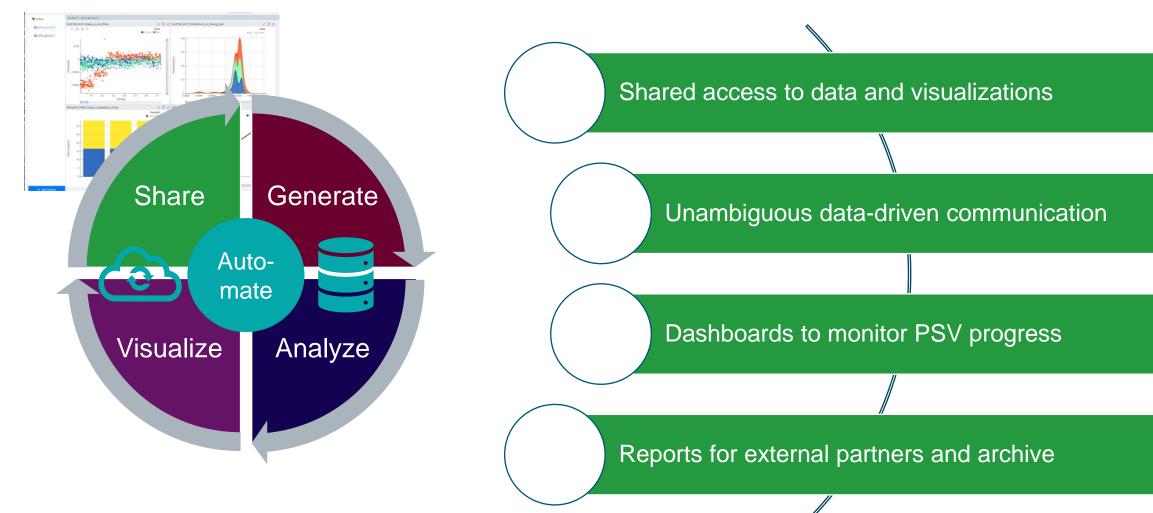
### PSV-specific visual analytics for fast insight





# Share

## More efficient, unambiguous communication across the globe, 24/7



## Conclusion

The current PSV
methodology does not
hold for modern complex
designs

Traditional methods do not find unexpected problems and are shown to be inefficient

We have come up with a new methodology and tools which deal with these challenges